

Phillips Scientific

16 Channel Time to Digital Converter

CAMAC MODEL 7186 7186H

FEATURES

- * Model 7186 Features NIM Inputs with LEMO Connectors
- * Model 7186H Features Differential ECL Header Connector Inputs
- * Less Than 7.2 μ Sec Conversion and Processing Time
- * 12-Bit Dynamic Range, Resolution down to 25pSec/Count
- * Programmable Pedestal Correction
- * Sparse Data Scan with Lower and Upper Time Cuts
- * Fast CLEAR and INHIBIT
- * COMMON START or COMMON STOP
- * Built-in Test Features Check TAC and Digitization

DESCRIPTION

The Model 7186/H TDC implements 16 channels of Time to Amplitude Conversion (TAC) followed by a digital processing section and CAMAC interface in a single width CAMAC module. To minimize data readout time, the module performs a sparse data function. Channels can be individually programmed with pedestal correction and both lower and upper level thresholds. Digitization starts following the COMMON input. It may be delayed by a user-programmable amount to allow time for derivation of fast CLEAR signals.

Channels that meet the sparsification requirements will have corresponding bits set in the Hit Register. Subsequent events will be ignored until the Hit Register is cleared either by completing a sparse read of the module or via front panel fast CLEAR or CAMAC Clear commands.

Four user selectable time ranges are provided in a given configuration:

Standard Configuration		Alternate Configuration	
Range	Resolution	Range	Resolution
100 nSec	25 pSec	1 μ Sec	.25 nSec
200 nSec	50 pSec	2 μ Sec	.50 nSec
400 nSec	100 pSec	4 μ Sec	1.0 nSec
800 nSec	200 pSec	8 μ Sec	2.0 nSec

Note: All channels need not have the same scale factors. Custom ranges are available when ordering.

INDIVIDUAL START or STOP INPUTS

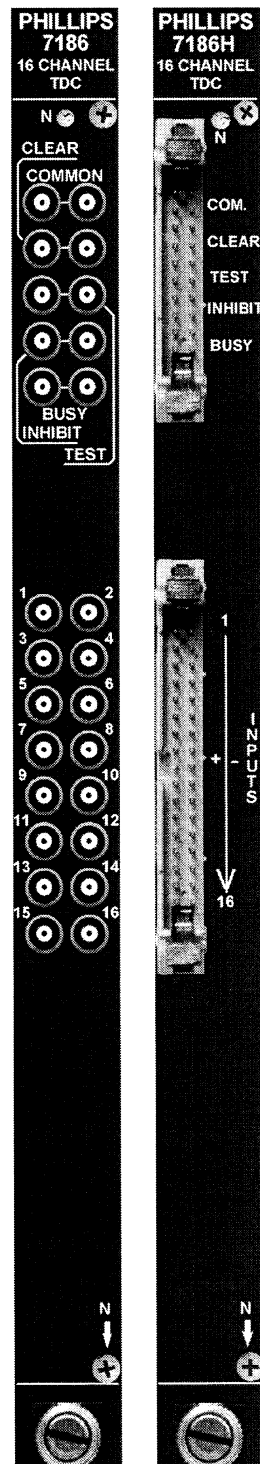
7186 : Fast negative NIM, direct-coupled input, (50 ohm impedance); Minimum pulse width 10nSec.

7186H : 100 ohm, differential ECL, 100mV threshold. Minimum input pulse width 10nSec.

COMMON, CLEAR, INHIBIT and TEST INPUTS

7186 : Two bridged LEMO inputs to facilitate daisy chaining, (5.1K ohm impedance). Terminate at end of chain with 50 ohms.

7186H : Two pairs of differential ECL inputs to facilitate daisy chaining. Terminate at end of chain with 110 ohms.



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Conversion Time : Less than 7.2 μ Sec, includes 750nSec prior to digitization for settling and for accepting CLEAR signals. Conversion is triggered by the leading edge of COMMON. Digitization may be delayed by 0 to 16 μ Sec in 62.5nSec increments with external jumpers. An increased delay is mandatory in the slower ranges of COMMON START mode and may be used in either mode to allow a greater acceptance window for CLEAR signals. For ranges above 800nSec full scale, increasing the delay by more than 4 μ Sec after the first STOP may result in a degradation in module performance.

CLEAR Input : Resets the Hit Register and the front ends as follows:
100, 200, 400, 800nSec ranges:
t < (COMMON - 850nSec): Resets any channels that have received START signals; no effect on digitization.
(COMMON - 700nSec) < t < Start of Digitization: Resets front ends and aborts digitization cycle.
t > Start of Digitization: Resets front ends; no effect on digitization.
1, 2, 4, 8 μ Sec Ranges:
t < (COMMON - 2.2 μ Sec): Resets any channels that have received START signals; no effect on digitization.
(COMMON - 1.9 μ Sec) < t < Start of Digitization: Resets front ends and aborts digitization cycle.
t > Start of Digitization: Resets front ends; no effect on digitization.
BUSY is asserted following CLEAR to allow time for the front ends to fully reset.

INHIBIT : Inhibits TAC and digitization. Must be removed at least 10nSec before START or COMMON signals for those signals to be recognized. To inhibit the front ends, INHIBIT must be applied no later than the START signal. To inhibit digitization, INHIBIT must be present 10nSec before COMMON.

TEST Input : Applies STOP/START signal to all channels. Used in conjunction with the COMMON START/STOP input to test operation of the TDC anywhere within the selected range.

BUSY Output

7186 : LEMO output connector. Double amplitude NIM current switching bridged output (32mA).
7186H : Differential ECL output. Two double row connector pins.
Active as follows:
– From receipt of COMMON until the event has been aborted by CLEAR or has been fully digitized and read out through the sparse data port. BUSY follows the Hit Register and thus may also be released by clearing the Hit Register.
– For 800nSec following fast CLEAR (2.4 μ Sec for ranges greater than or equal 1 μ Sec)
– During any CAMAC addressing of the module.

FRONT END PERFORMANCE

A dithered mode may be selected by the user for improved performance for spectroscopy analysis. It should be disabled when working within the bottom or top 1.5% of the module's range or for those measurements not creating histograms of data.

Linearity : Integral : Less than 4 counts over 10% to 90% of range.
Differential : Less than 0.025% of full scale maximum.
Non-Dithered: ± 0.5 bins typical DNL.
Dithered: ± 0.1 bins typical DNL.

FRONT END PERFORMANCE (continued)

Noise, Jitter : Typically less than 20 pSec RMS.

Crosstalk : Less than 3 LSB between adjacent channels.

START/STOP : 20nSec internal offset; Front ends are offset by this amount for improved linearity and to allow use of full dynamic range.

Stability : Gain : 100 ppm/°C typically. Offset : 0.15 counts/°C typically.

Power Supply Requirements : + 6V @ 2.1 Amp typically
- 6V @ 2.2 Amp typically
+24V @ 180 mA typically
Forced air cooling is recommended.

ADDITIONAL TEST FEATURES

Calibration Check : Simulates a START/STOP sequence under CAMAC control to verify operation of the module. CAMAC selectable nominal 1/3 or 2/3 full scale calibration for each full scale range. Not intended for use in calibrating the module.

CAMAC Check : Loads a predetermined pattern to simulate the outputs of the A/D converters. Useful for verifying the operation of the digital processing sections of the module.

SPARSIFICATION and LAM OPERATION

Separate pedestals and upper and lower thresholds may be set for each channel. They are enabled using bits in the Control Register. Pedestals in signed 2's complement format are added to the data before threshold comparison. Bits in the Hit Register are set during digitization for those channels whose pedestal corrected data falls within their upper and lower thresholds. If enabled, LAM is set whenever a bit in the Hit Register is set. Sparse data reads present only those channels with bits set in the Hit Register, starting with the highest numbered channel. As channels are read, their Hit Register bits are reset; when the final channel has been read LAM is reset. LAM is also reset when the Hit Register is reset.

DATA WORD FORMAT

16	13	12	1
Channel ID		Channel Data	

CONTROL REGISTER FORMAT

16	9	8	4	3	2	1
Conversion Delay (Read Only)		0	UT Enable	LT Enable	PED Enable	

CAMAC DATAWAY OPERATIONS

F(0)·A(X) : Read event data memory for Channel (X+1). Data word as described above.

F(1)·A(X) : Read the parameter memory pointed to by the most recent F17 operation for channel (X+1).

F(4)·A(0) : Read Sparse Data. Only those channels with data that falls between their upper and lower thresholds are read, starting with the highest numbered channel. Reading an empty buffer returns Q false. Data word as described above.

F(6)·A(0) : Read the Control Register. Format described above.

CAMAC DATAWAY OPERATIONS (continued)

- F(6)·A(1)** : Read the Hit Register. Shows which channels' pedestal corrected data falls within their upper and lower thresholds.
- F(8)** : Test LAM. A Q=1 response is generated if LAM is present and enabled. The address lines have no effect on this command.
- F(9)** : Clears the Module. Resets front end, clears and disables LAM, disables pedestals and thresholds. The address lines have no effect on this command.
- F(10)** : Clears LAM. Occurs on S2 strobe. The address lines have no effect on this command.
- F(11)·A(0)** : Reset the Control Register. Occurs on S2 strobe.
- F(11)·A(1)** : Reset the Hit Register and LAM. No effect on data memory. Occurs on S2 strobe.
- F(11)·A(2)** : Reset the Test Register. Occurs on S2 strobe.
- F(11)·A(3)** : Reset the Hit Register, LAM and data memory. Occurs on S2 strobe.
- F(16)·A(X)** : Write to data memory for channel (X+1).
- F(17)·A(0)** : Select the Pedestal Memory for the next F1 or F20 operation.
- F(17)·A(1)** : Select the Lower Threshold Memory for the next F1 or F20 operation.
- F(17)·A(2)** : Select the Upper Threshold Memory for the next F1 or F20 operation.
- F(17)·A(4)** : Select the Test Register for the next F20 operation.
- F(19)·A(0)** : Set the Control Register bits. Format described above.
- F(20)·A(X)** : Write the pedestal, upper or lower threshold for Channel (X+1) as selected by the most recent F17 operation. Pedestal range is ± 4095 ; threshold ranges are 0 to 4095.
Program the test register if it was selected by the most recent F17 operation.
A0 : Test pattern = 001001001001
A1 : Test pattern = 010010010010
A2 : Test pattern = 100100100100
A3 : Test pattern = 111111111111
- F(23)·A(0)** : Reset the Control Register bits. Format described above.
- F(24)** : Disable LAM. Occurs on the S2 strobe. The address lines have no effect on this command.
- F(25)·A(0)** : Digital test. Initiates a data acquisition cycle using the value stored in the Test Register by the most recent F20 command.
- F(25)·A(1)** : Test. Initiates a data acquisition cycle using a simulated event of approximately 1/3 full scale applied to the front end.
- F(25)·A(2)** : Test. Runs a data acquisition cycle using a simulated event of approximately 2/3 full scale applied to the front end.
- F(26)** : Enable LAM. Enables LAM on the S1 strobe. The address lines have no effect on this command.
- C, Z** : Reset the front end, clear and disable the LAM, disable pedestal and thresholds and clear the Hit Register. Occurs on the S2 strobe.
- I** : Inhibits TDC Front End.